

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KEENAN ET AL.	
		Examiner Navneet K. Ahluwalia	Art Unit 2166	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,925,608 B1	08-2005	Neale et al.	715/763
*	B	US-6,789,076 B1	09-2004	Dutta, Rabindranath	707/5
*	C	US-2004/0059729 A1	03-2004	Krupin et al.	707/003
*	D	US-2003/0212666 A1	11-2003	Basu et al.	707/3
*	E	US-2003/0126235 A1	07-2003	Chandrasekar et al.	709/220
*	F	US-2003/0069873 A1	04-2003	FOX et al.	707/1
*	G	US-2002/0107853 A1	08-2002	Hofmann et al.	707/7
*	H	US-6,886,009 B2	04-2005	Jeng et al.	707/3
*	I	US-6,876,997 B1	04-2005	Rorex et al.	707/3
*	J	US-6,751,611 B2	06-2004	Krupin et al.	707/3
*	K	US-6,415,282	07-2002	Mukherjea et al.	707/3
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.